



DOCKET NO.: 3905

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
IN THE MATTER OF THE APPLICATION FOR PATENT

OF: Takao NAKAMURA et al.

| ART UNIT: 2814

SERIAL NO.: 09/519,408

| Conf. No.: 7245

FILED: March 3, 2000

| Ex.: W. S. Louie

FOR: Semiconductor Light-Emitting Device,
Method of Manufacturing Transparent
Conductor film and Method of Manu-
facturing Compound Semiconductor
Light-Emitting Device

MS AF
COMMISSIONER FOR PATENTS
P.O. BOX 1450
ALEXANDRIA, VA 22313-1450

September 8, 2003

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INFORMATION DISCLOSURE STATEMENT WITH CERTIFICATE OF MAILING

Dear Sir:

- 1) Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98 applicants enclose a Seventh Form PTO-1449. A copy of the reference listed thereon and a copy of a Chinese Office Action (and English translation thereof) issued in a counterpart Chinese Patent application on June 20, 2003 are enclosed.
- 2) In accordance with 37 C.F.R. 1.97(d), this IDS is being filed before payment of the issue fee, includes the required certification (see next paragraph), and is accompanied by a

09/12/2003 RHEBRAHT 00000040 09519408

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180.00 OP

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Credit Card Payment Form (PTO-2038) to cover the required fee of \$180.00.

- 3) The undersigned attorney hereby certifies that each reference being cited in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement, as seen from the Chinese Office Action date of June 20, 2003.
- 4) Reference AF2 (US 5,741,580) is a partial counterpart and claims the priority (among others) of Japanese Patent Application 7-217099 which was published as Japanese Publication 9-59762, which was cited as reference AB in our Second IDS of July 31, 2000. The other references listed in the Chinese Office Action were previously cited herein as reference AA in our Information Disclosure Statement of March 3, 2000 (and as reference "N" in the Office Action of June 6, 2001), and as references AI, AP and AQ in our Information Disclosure Statement of June 18, 2002.
- 5) The present reference AF2 is in English, and no discussion thereof is required. The enclosed English translation of the Chinese Office Action shows why the Chinese Examiner found the cited references to be relevant. The Chinese Examiner's remarks are not ratified or adopted as accurate, but are submitted for

the U. S. Examiner's consideration as to the relevance of the references.



Applicants respectfully request that the Examiner consider all references of record, return an initialled copy of the enclosed Form PTO-1449 and ensure that all references of record are printed on any patent issuing from this application.

Respectfully submitted,

Takao NAKAMURA et al.
Applicant

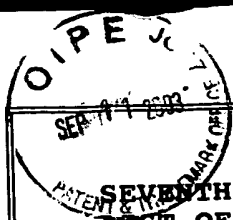
WFF:ar/3905
Enclosure: postcard,
Seventh Form PTO-1449,
copy of Chinese Office Action
& English Translation thereof,
1 reference,
Form PTO-2038

By Walter F. Fasse
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CERTIFICATE OF MAILING:

I hereby certify that this correspondence with all indicated enclosures is being deposited with the U. S. Postal Service with sufficient postage as first-class mail, in an envelope addressed to: COMMISSIONER FOR PATENTS, P.O. BOX 1450, ALEXANDRIA, VA 22313-1450 on the date indicated below.

Walter F. Fasse 9/8/03
Name: Walter F. Fasse - Date: September 8, 2003

Sheet 1 of 1Atty. Docket No.
3905Serial No.:
09/519,408

SEVENTH
LIST OF REFERENCES CITED BY
APPLICANT
(REVISED FORM PTO-1449)
DATED: September 8, 2003

Applicant: Takao NAKAMURA et al.

U.S. Filing Date:
March 3, 2000Art Unit:
2814

U. S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	Cl.	Sub- Cl.	File Date
	AF2	5741580	04/1998	Hayamizu et al.	-	-	-

FOREIGN PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	COUNTRY	Cl.	Sub- Cl.	Trans.	
							Yes	No

OTHER DOCUMENTS

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.